

# Supporting Information

## Efficient and Selective Removal of Palladium from Simulated High-Level Liquid Waste Using a Silica-Based Adsorbent NTAamide(C8)/SiO<sub>2</sub>-P

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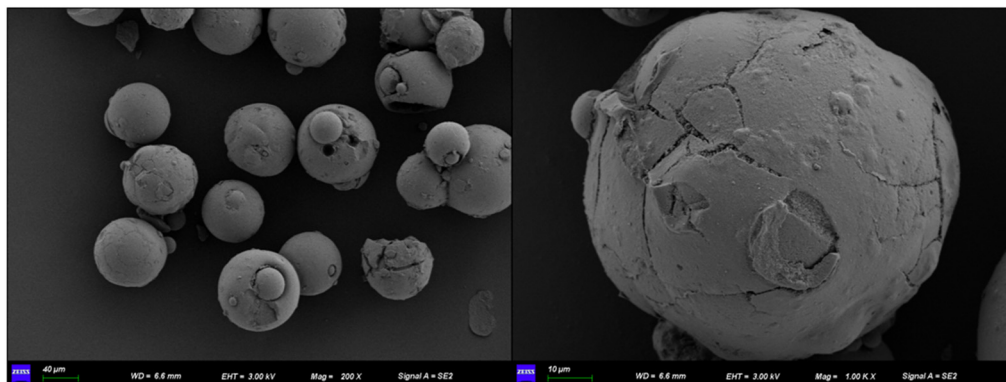
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### 3. Results

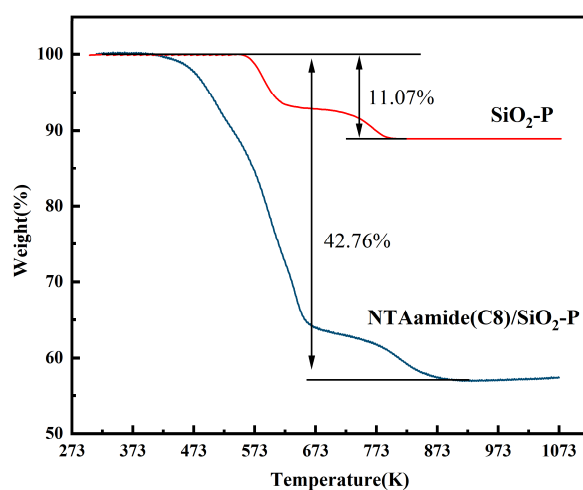
#### 3.1. Characterization

To determine the morphology of the carrier, SEM characterization was performed. The SEM results of SiO<sub>2</sub>-P are shown in Figure S1. The surface of /SiO<sub>2</sub>-P sphere is relatively rough, ensuring its high specific surface area. It is beneficial for loading more ligands.



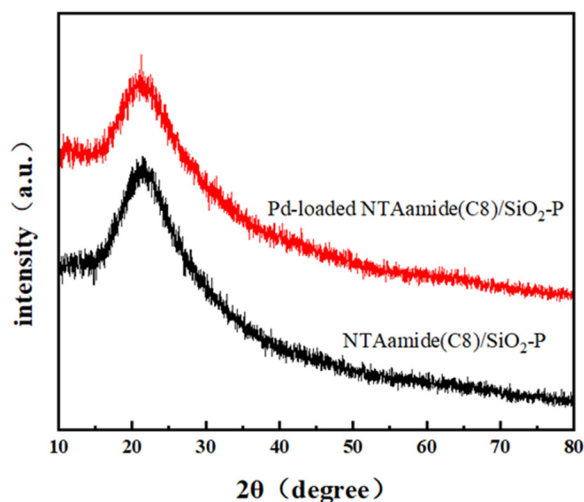
**Figure. S1** SEM images of SiO<sub>2</sub>-P.

To determine the organic content in NTAamide(C8)/SiO<sub>2</sub>-P, a TG thermal analyzer was used to test the decomposition curve under a nitrogen atmosphere with a heating rate of 5 K/min from room temperature to 1073 K. As shown in Figure S2, the TG curve shows continuous weight loss as the test temperature increases. The weight loss of NTAamide (C8)/SiO<sub>2</sub>-P (42.76%) starts at around 413 K and completes at 893 K, which is attributed to the decomposition of the polymer and ligand portion in NTAamide (C8). The SiO<sub>2</sub> remained stable above 893 K with a content of 57.24%. According to the TG curve of SiO<sub>2</sub>-P, the content of the inert copolymer in the SiO<sub>2</sub>-P particles obtained is 11.07 %. By calculating, the content of NTAamide(C8) in the adsorbent is 35.63 %.



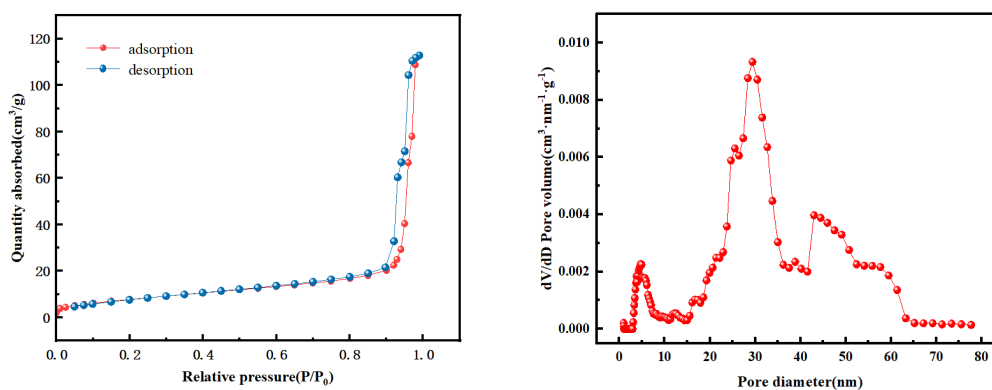
**Figure. S2** TG curves of NTAamide(C8)/SiO<sub>2</sub>-P and SiO<sub>2</sub>-P.

The XRD patterns of NTAamide(C8)/SiO<sub>2</sub>-P and Pd-loaded NTAamide(C8)/SiO<sub>2</sub>-P (Figure S3) exhibit a wide diffraction peak from 15 to 25°, consistent with the pattern of SiO<sub>2</sub>-P. It indicates that silica remains in an amorphous state during the synthesis and adsorption processes.



**Figure. S3** XRD patterns of NTAamide(C8)/SiO<sub>2</sub>-P and Pd-loaded NTAamide(C8)/SiO<sub>2</sub>-P.

The N<sub>2</sub>-adsorption-desorption isotherm and pore diameter distribution of NTAamide(C8)/SiO<sub>2</sub>-P (Figure S4) suggest its mesoporous structure. The calculated specific surface area, pore volume, and average pore size are shown in Table S1.



**Figure. S4** N<sub>2</sub>-adsorption-desorption isotherm and pore diameter distribution of NTAamide(C8)/SiO<sub>2</sub>-P.

**Table. S1** Main parameters of SiO<sub>2</sub>-P and NTAamide(C8)/SiO<sub>2</sub>-P obtained from BET.

Materials	BET area(m <sup>2</sup> /g)	surface Pore (cm <sup>3</sup> /g)	volume Average diameter(nm)	pore
NTAamide(C8)/SiO <sub>2</sub> -P	26.4	0.17	29.4	